Application/Control No. Applicant(s)/Patent Under Reexamination 10/815,398 YUEH ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Sin J. Lee 1752 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-2005/0147915 A1 Α 07-2005 Dammel, Ralph R. 430/270.1 В US-С US-D US-Ε US-F US-G US-Н US-US-1 J US-K US-US-L US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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